# **800V N-Channel MOSFET**



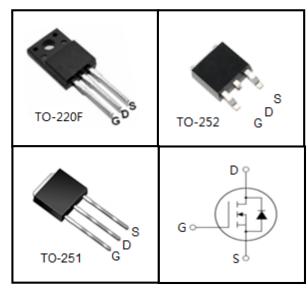
### **FEATURES**

- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

### **APPLICATIONS**

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)

Device Marking and Package Information				
Device	Package Marking			
RS4N80F	TO-220F	RS4N80F		
RS4N80M	TO-251	RS4N80M		
RS4N80D	TO-252	RS4N80D		



<b>Absolute Maximum Ratings</b> T <sub>C</sub> = 25°C, unless otherwise noted						
Poromotor	Symbol	Value			l lmit	
Parameter		TO-220F	TO-252	TO-251	Unit	
Drain-Source Voltage (V <sub>GS</sub> = 0V)	V <sub>DSS</sub>	800		V		
Continuous Drain Current	I <sub>D</sub>	3		А		
Pulsed Drain Current (note1)	I <sub>DM</sub>	12		А		
Gate-Source Voltage	V <sub>GSS</sub>	±30		V		
Single Pulse Avalanche Energy (note2)	E <sub>AS</sub>	160		mJ		
Avalanche Current (note1)	I <sub>AR</sub>	3		А		
Repetitive Avalanche Energy (note1)	E <sub>AR</sub>	20		mJ		
Power Dissipation (T <sub>C</sub> = 25°C)	P <sub>D</sub>	25 70		W		
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55~+150		°C		

Thermal Resistance					
Parameter	Symbol	Value			1114
		TO-220F	TO-252	TO-251	- Unit
Thermal Resistance, Junction-to-Case	R <sub>thJC</sub>	5	1.78		K/W
Thermal Resistance, Junction-to-Ambient	R <sub>thJA</sub>	62.5	60		IN/VV

<b>Specifications</b> $T_J = 25^{\circ}C$ , ur  Parameter	Symbol		Value			
		Test Conditions	Min.	Тур.	Max.	Unit
Static				7.		
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0V, I_D = 250\mu A$	800			V
	I <sub>DSS</sub>	$V_{DS} = 800V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1	
Zero Gate Voltage Drain Current		V <sub>DS</sub> = 640V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125°C			100	<del>-</del> μΑ
Gate-Source Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 30V$			±100	nA
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3.0		4.0	V
Drain-Source On-Resistance (Note3)	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 1.5A		3	3.6	Ω
Dynamic						
Input Capacitance	C <sub>iss</sub>	V 0V		793		pF
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0V,$ $V_{DS} = 25V,$		63		
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0MHz		9		
Total Gate Charge	$Q_g$			19		nC
Gate-Source Charge	$Q_{gs}$	$V_{DD} = 640V, I_{D} = 3A, V_{GS} = 10V$		3		
Gate-Drain Charge	$Q_{gd}$	93		9		
Turn-on Delay Time	t <sub>d(on)</sub>			12		
Turn-on Rise Time	t <sub>r</sub>	$V_{DD} = 400V, I_{D} = 3A,$		20		ns
Turn-off Delay Time	t <sub>d(off)</sub>	$R_G = 25 \Omega$		30		
Turn-off Fall Time	t <sub>f</sub>			45		
Drain-Source Body Diode Character	istics					
Continuous Body Diode Current	I <sub>S</sub>				3	۸
Pulsed Diode Forward Current	I <sub>SM</sub>	T <sub>C</sub> = 25 °C			12	А
Body Diode Voltage	V <sub>SD</sub>	$T_J = 25^{\circ}C$ , $I_{SD} = 3A$ , $V_{GS} = 0V$			1.4	V
Reverse Recovery Time	t <sub>rr</sub>	$V_{GS} = 0V, I_{S} = 3A,$		300		ns
Reverse Recovery Charge	Q <sub>rr</sub>	di <sub>F</sub> /dt =100A /μs		2.6		μC

### Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2.  $I_{AS}$  = 3A,  $V_{DD}$  = 50V,  $R_{G}$  = 25  $\Omega$ , Starting  $T_{J}$  = 25  $^{\circ}C$
- 3. Pulse Test: Pulse width ≤ 300µs, Duty Cycle ≤ 1%

**Typical Characteristics**  $T_J = 25^{\circ}\text{C}$ , unless otherwise noted

Figure 1. Output Characteristics ( $T_J = 25^{\circ}C$ )

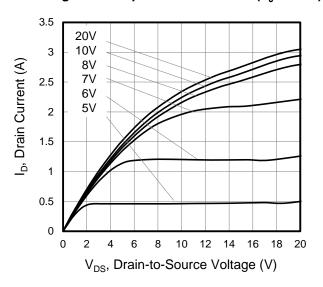


Figure 3. Drain Current vs. Temperature

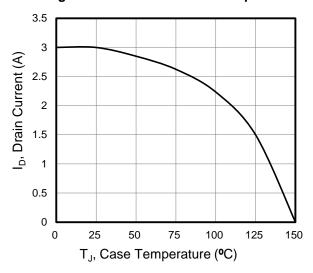


Figure 5. Transfer Characteristics

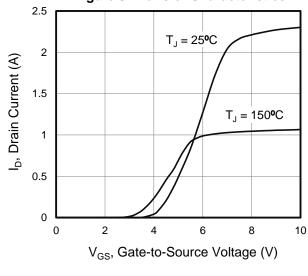


Figure 2. Body Diode Forward Voltage

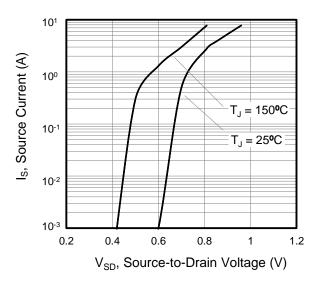


Figure 4.  $BV_{DSS}$  Variation vs. Temperature

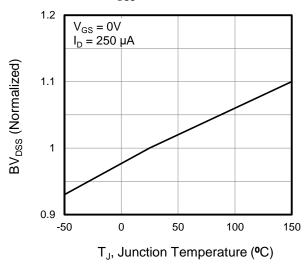
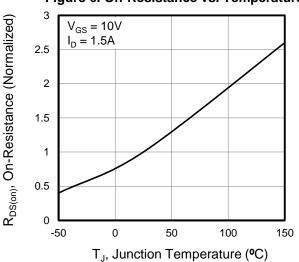


Figure 6. On-Resistance vs. Temperature



**Typical Characteristics**  $T_J = 25^{\circ}\text{C}$ , unless otherwise noted

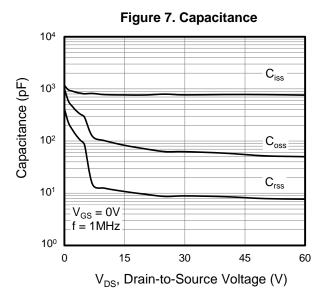
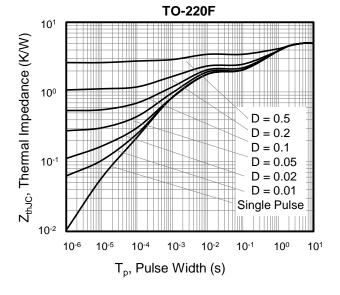


Figure 9. Transient Thermal Impedance



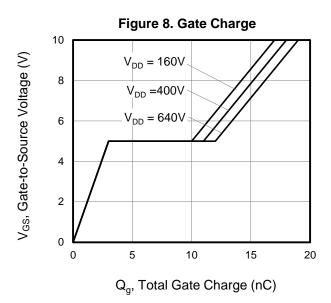


Figure 10. Transient Thermal Impedance

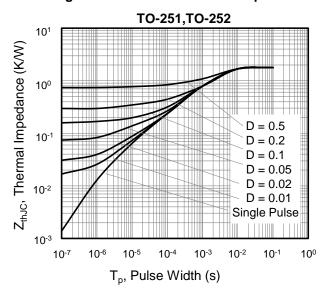


Figure A: Gate Charge Test Circuit and Waveform

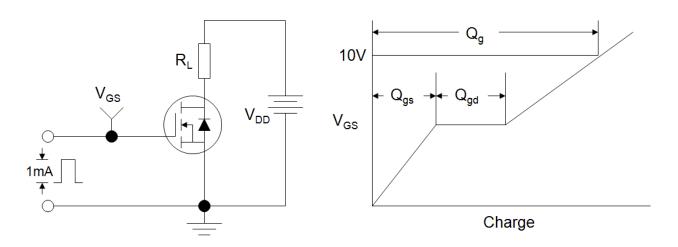


Figure B: Resistive Switching Test Circuit and Waveform

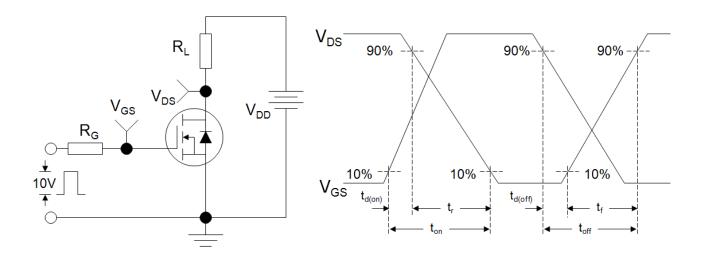
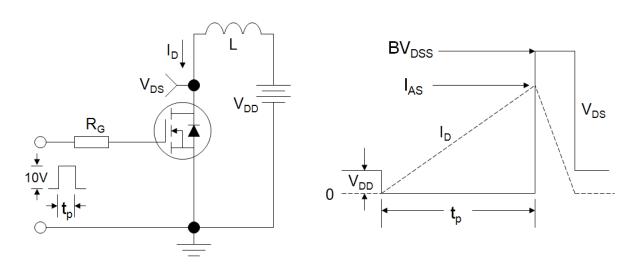
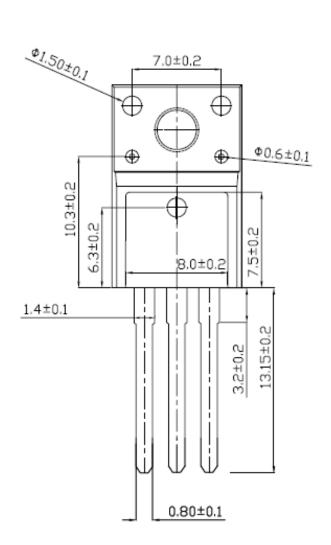
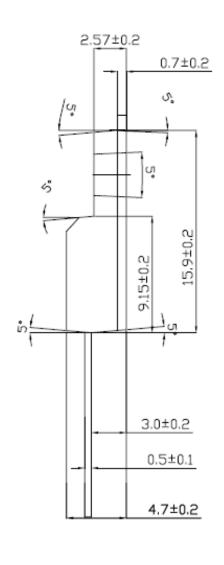


Figure C: Unclamped Inductive Switching Test Circuit and Waveform

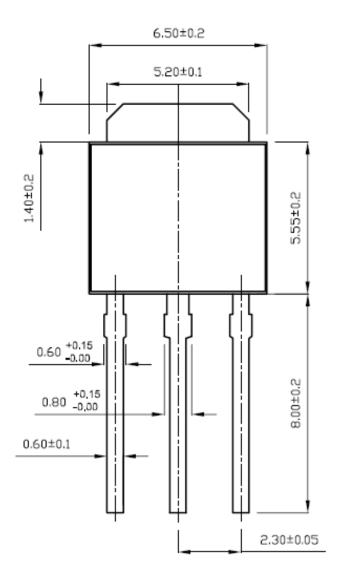


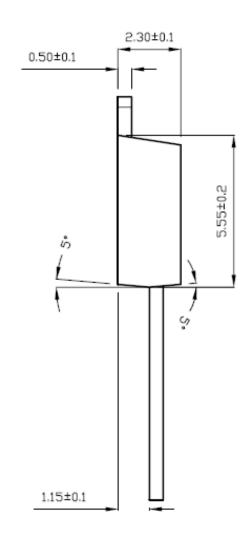
# **TO-220F**



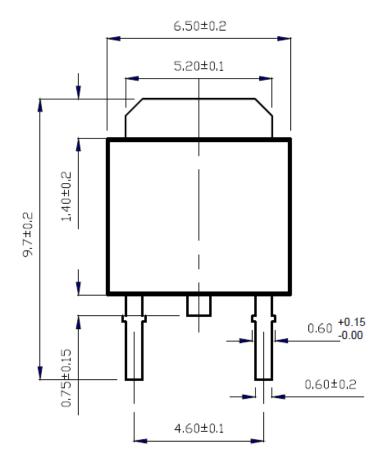


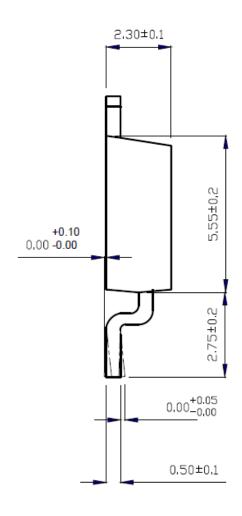
TO-251





**TO-252** 





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